

**Search Notes**

Application/Control No.

10/694,227

Examiner

James W. Cranson

Applicant(s)/Patent under  
Reexamination

CHIEH ET AL.

Art Unit

2875

**SEARCHED**

Class	Subclass	Date	Examiner
362	500	8/7/2005	JWC
362	800	8/7/2005	JWC
315	76	8/7/2005	JWC
362	487	8/7/2005	JWC
362	478	8/7/2005	JWC
362	192	8/7/2005	JWC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
TEXT 362/\$.CCLS.	8/7/2005	JWC
TEXT 315/\$.CCLS	8/7/2005	JWC